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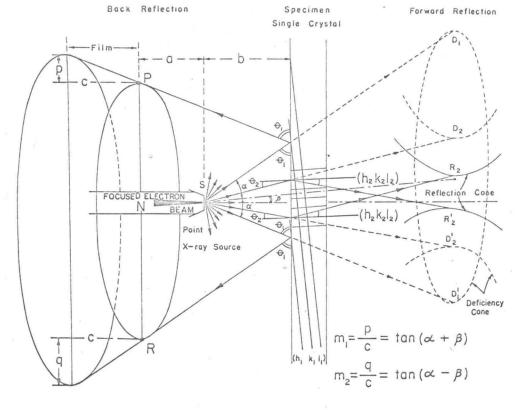


Fig. 1. Schematic repcontation of the genertion of pseudo-Kossel atterns by the diverreat beam method.

## 2. DESCRIPTION OF METHOD

The divergent beam method utilizes a long, horizontal av tube, shown schematically in Fig. 1. An electron am originating from an electron gun is focused by ans of an electromagnetic lens onto the tip of the auum-tight tube closed by a thin metal foil.7 Since s metal foil is bombarded by the electron beam, it actions as an x-ray target. By operating the tube at a table voltage, an x-ray beam composed mainly of tracteristic radiation emerges from the tip of the tube, Abiting a divergence of nearly 180°. At the point of ergence the beam size is about 10  $\mu$  in diameter. When beam impinges on the specimen, which is placed at stance of 0.4–3 mm from the tip of the tube, diffraca patterns of the characteristic spectrum in transsion as well as in the back-reflection region may be orded. We shall be principally concerned with the lysis of the back-reflection patterns, since these can obtained conveniently even from thick specimens, exposure time for a tungsten crystal being only The technique of measuring the back-reflection tern, which will be subsequently described in detail, with some slight modification, equally applicable to smission patterns.

The divergent beam patterns are analogous to the known Kossel patterns, except that the former are

produced by an x-ray source located outside instead of inside the crystal. Therefore, we refer to them as pseudo-Kossel patterns.

The diffraction cones intersect the film in ellipse-like figures (Figs. 1 and 2); and although these figures, strictly speaking, represent curves of higher orders, we shall refer to them as ellipses.

Each ellipse corresponds to a reflection from a definite (hkl) set of planes, the d spacing of which can be ac-

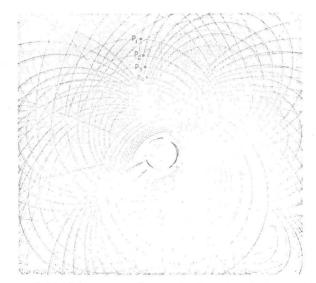


Fig. 2. Multiple exposure photograph of tungsten single crystal.

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We tay tube of this type and a diffraction unit ("Microflex") commercially produced by the Rigaku-Denki Company, lapan.